

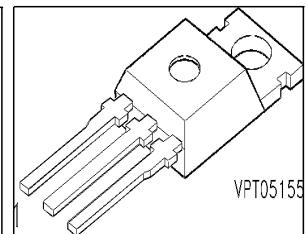
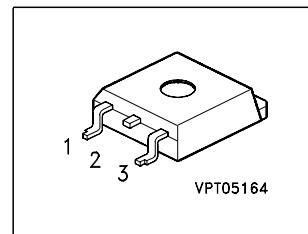
SIPMOS® Power Transistor

Features

- N channel
- Enhancement mode
- Avalanche rated
- dv/dt rated
- 175°C operating temperature

Product Summary

Drain source voltage	V_{DS}	30	V
Drain-Source on-state resistance	$R_{DS(on)}$	0.015	Ω
Continuous drain current	I_D	46	A



Type	Package	Ordering Code	Packaging	Pin 1	Pin 2	Pin 3
SPP46N03	P-TO220-3-1	Q67040-S4742-A2	Tube	G	D	S
SPB46N03	P-TO263-3-2	Q67040-S4145-A3	Tape and Reel			

Maximum Ratings, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current $T_C = 25^\circ\text{C}, 1)$	I_D	46	A
$T_C = 100^\circ\text{C}$			
Pulsed drain current $T_C = 25^\circ\text{C}$	$I_{D\text{pulse}}$		
Avalanche energy, single pulse $I_D = 46 \text{ A}, V_{DD} = 25 \text{ V}, R_{GS} = 25 \Omega$	E_{AS}	250	mJ
Avalanche energy, periodic limited by $T_{j\text{max}}$	E_{AR}	12	
Reverse diode dv/dt $I_S = 46 \text{ A}, V_{DS} = 24 \text{ V}, di/dt = 200 \text{ A}/\mu\text{s}, T_{j\text{max}} = 175^\circ\text{C}$	dv/dt	6	kV/ μs
Gate source voltage	V_{GS}	± 20	V
Power dissipation $T_C = 25^\circ\text{C}$	P_{tot}	120	W
Operating and storage temperature	T_j, T_{stg}	-55... +175	°C
IEC climatic category; DIN IEC 68-1		55/175/56	

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Characteristics					
Thermal resistance, junction - case	R_{thJC}	-		1.25	K/W
Thermal resistance, junction - ambient, leded	R_{thJA}	-	-	62	
SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ²⁾	R_{thJA}	-	-	62	
		-	-	40	

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Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Static Characteristics					
Drain- source breakdown voltage $V_{GS} = 0 \text{ V}$, $I_D = 0.25 \text{ mA}$	$V_{(BR)DSS}$	30	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 80 \mu\text{A}$	$V_{GS(\text{th})}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 30 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_j = 25^\circ\text{C}$ $V_{DS} = 30 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_j = 150^\circ\text{C}$	I_{DSS}		0.1	1	μA
Gate-source leakage current $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$	I_{GSS}	-	10	100	nA
Drain-Source on-state resistance $V_{GS} = 10 \text{ V}$, $I_D = 46 \text{ A}$	$R_{DS(\text{on})}$	-	0.009	0.015	Ω

¹current limited by bond wire

² Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6 cm² (one layer, 70μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Dynamic Characteristics					
Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}$, $I_D = 46 \text{ A}$	g_{fs}	20	39	-	S
Input capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{iss}	-	1400	1750	pF
Output capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{oss}	-	645	810	
Reverse transfer capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{rss}	-	260	325	
Turn-on delay time $V_{DD} = 15 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 46 \text{ A}$, $R_G = 6.8 \Omega$	$t_{d(on)}$	-	13	20	ns
Rise time $V_{DD} = 15 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 46 \text{ A}$, $R_G = 6.8 \Omega$	t_r	-	24	36	
Turn-off delay time $V_{DD} = 15 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 46 \text{ A}$, $R_G = 6.8 \Omega$	$t_{d(off)}$	-	27	42	
Fall time $V_{DD} = 15 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 46 \text{ A}$, $R_G = 6.8 \Omega$	t_f	-	24	36	

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

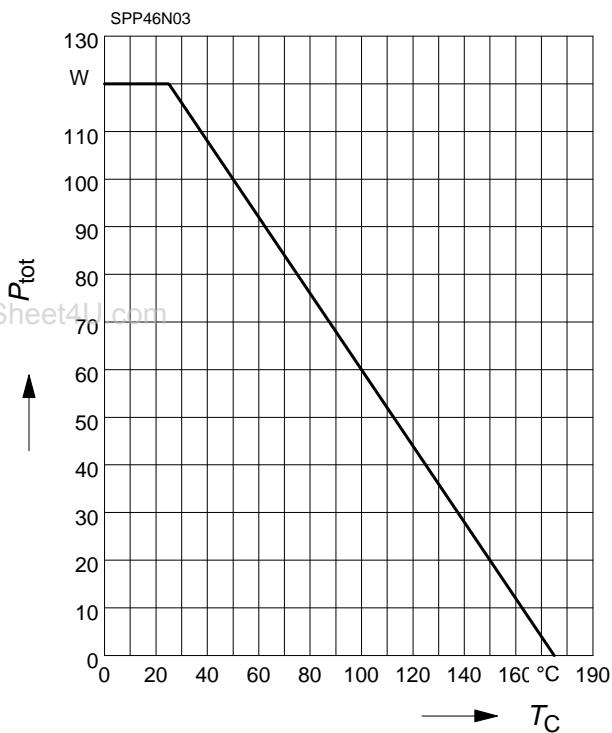
Gate to source charge $V_{DD} = 24 \text{ V}, I_D = 46 \text{ A}$	Q_{gs}	-	7	11	nC
Gate to drain charge $V_{DD} = 24 \text{ V}, I_D = 46 \text{ A}$	Q_{gd}	-	19	28.5	
Gate charge total $V_{DD} = 24 \text{ V}, I_D = 46 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$	Q_g	-	39	60	
Gate plateau voltage $V_{DD} = 24 \text{ V}, I_D = 46 \text{ A}$	$V_{(\text{plateau})}$	-	5.5	-	V

Reverse Diode

Inverse diode continuous forward current $T_C = 25^\circ\text{C}$	I_S	-	-	46	A
Inverse diode direct current,pulsed $T_C = 25^\circ\text{C}$	I_{SM}	-	-	184	
Inverse diode forward voltage $V_{GS} = 0 \text{ V}, I_F = 92 \text{ A}$	V_{SD}	-	1.06	1.7	V
Reverse recovery time $V_R = 15 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	t_{rr}	-	40	60	ns
Reverse recovery charge $V_R = 15 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	Q_{rr}	-	0.04	0.06	μC

Power Dissipation

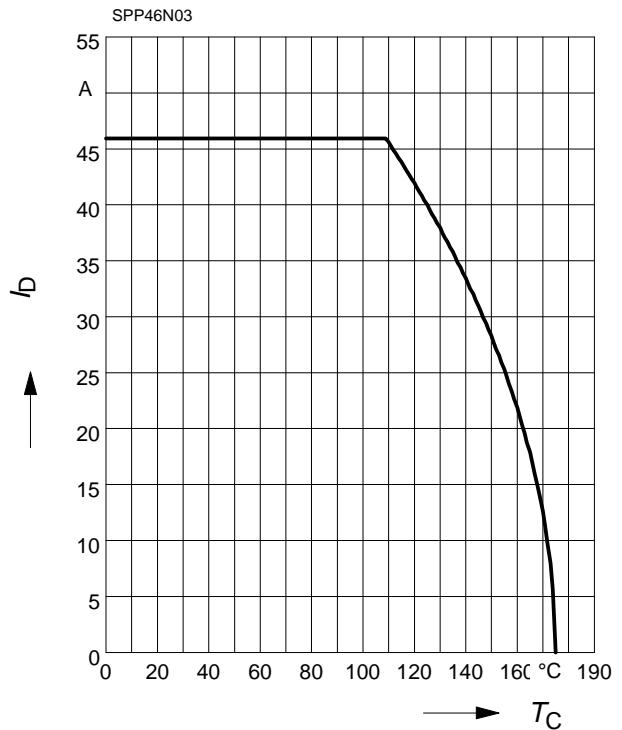
$$P_{\text{tot}} = f(T_C)$$



Drain current

$$I_D = f(T_C)$$

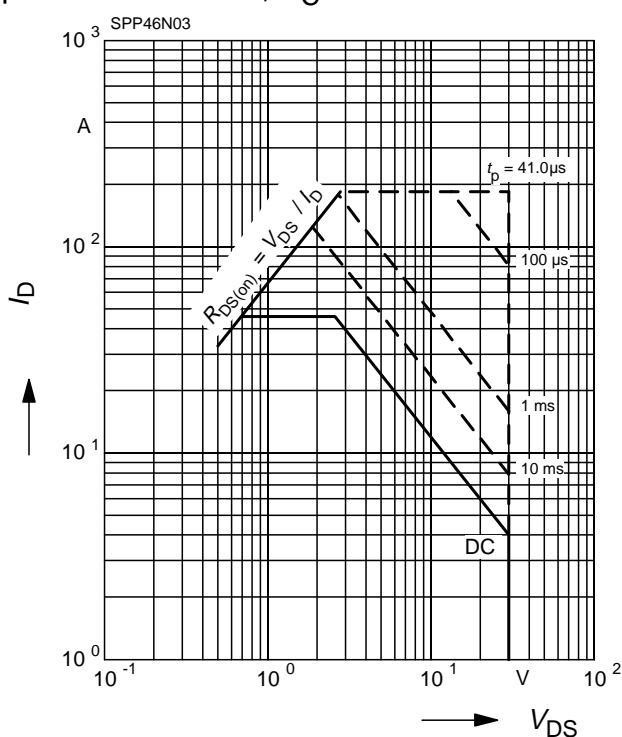
parameter: $V_{GS} \geq 10$ V



Safe operating area

$$I_D = f(V_{DS})$$

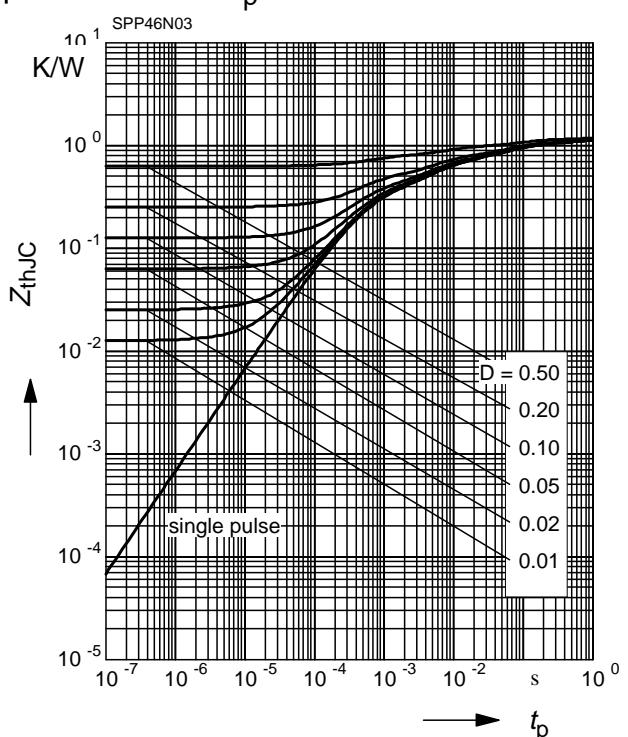
parameter : $D = 0$, $T_C = 25$ °C



Transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

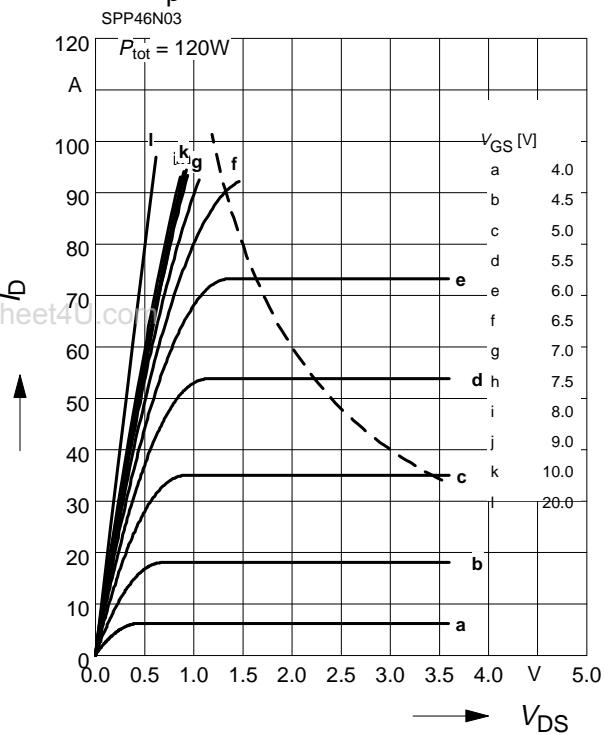
parameter : $D = t_p/T$



Typ. output characteristics

$$I_D = f(V_{DS})$$

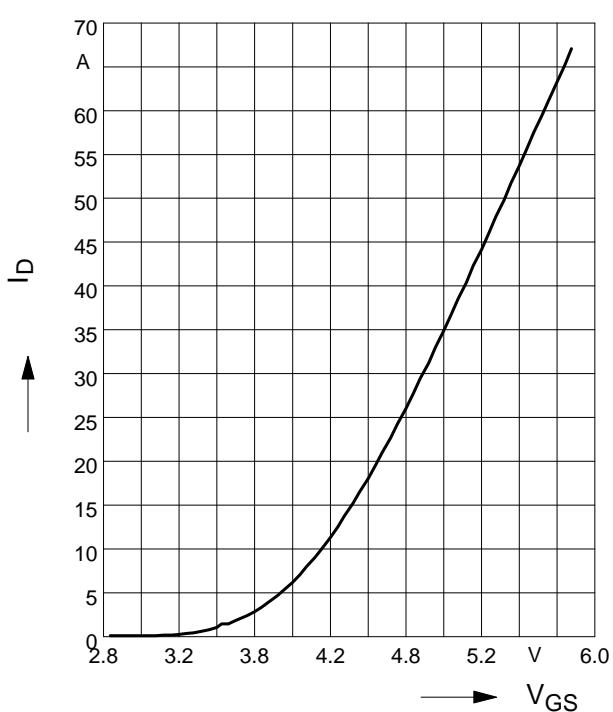
parameter: $t_p = 80 \mu\text{s}$



Typ. transfer characteristics $I_D = f(V_{GS})$

parameter: $t_p = 80 \mu\text{s}$

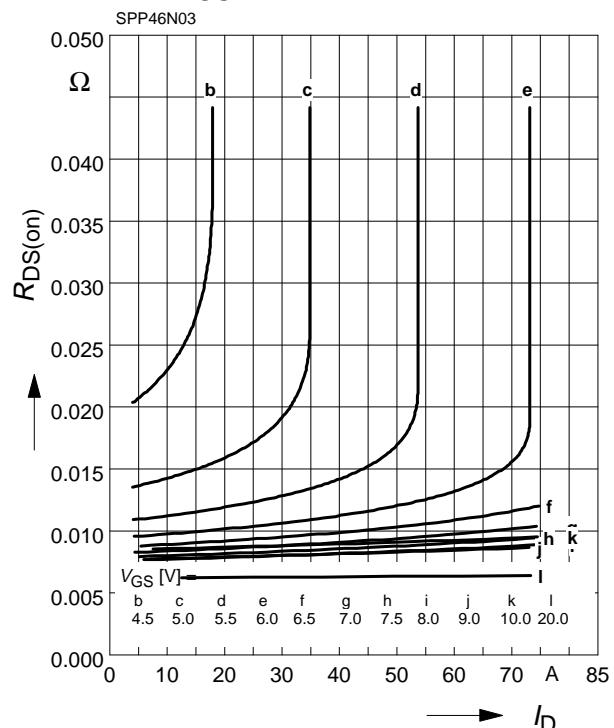
$$V_{DS} \geq 2 \times I_D \times R_{DS(\text{on})\max}$$



Typ. drain-source-on-resistance

$$R_{DS(\text{on})} = f(I_D)$$

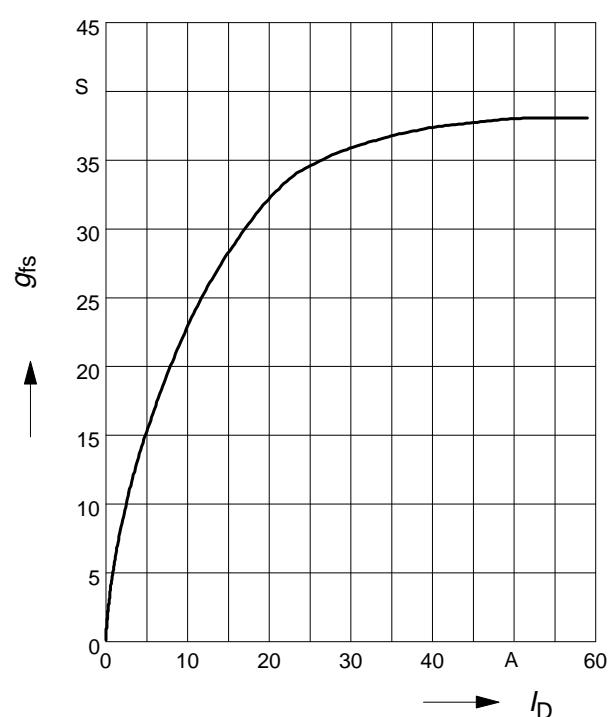
parameter: V_{GS}



Typ. forward transconductance

$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

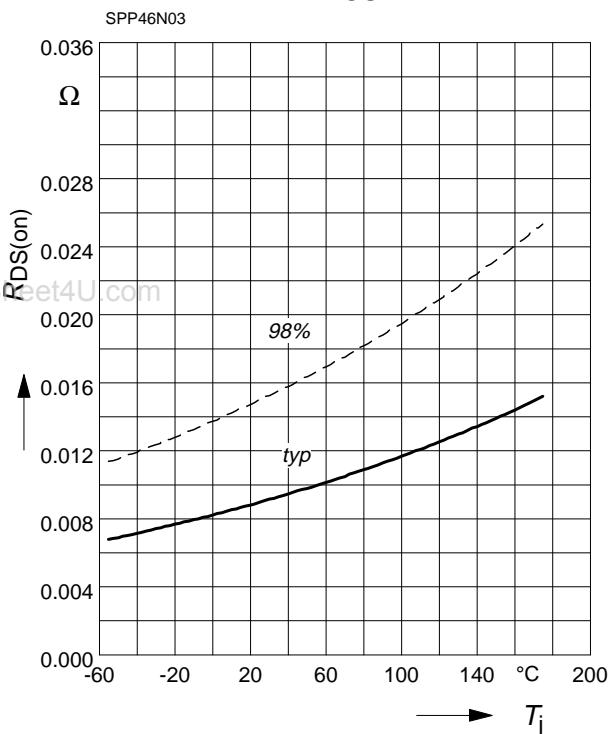
parameter: g_{fs}



Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

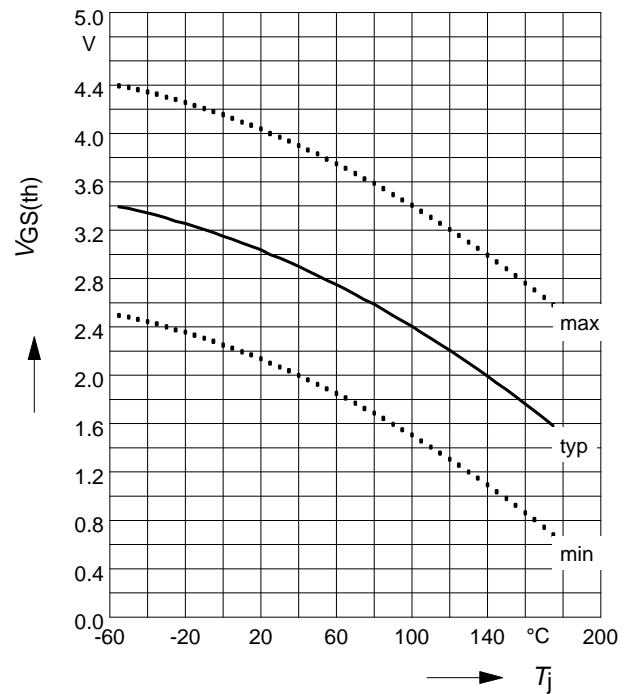
parameter : $I_D = 46 \text{ A}$, $V_{GS} = 10 \text{ V}$



Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

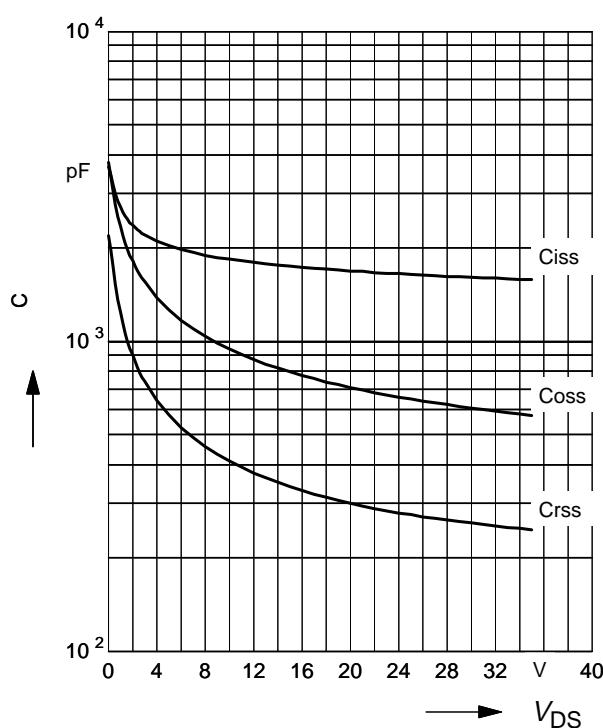
parameter : $V_{GS} = V_{DS}$, $I_D = 80 \mu\text{A}$



Typ. capacitances

$$C = f(V_{DS})$$

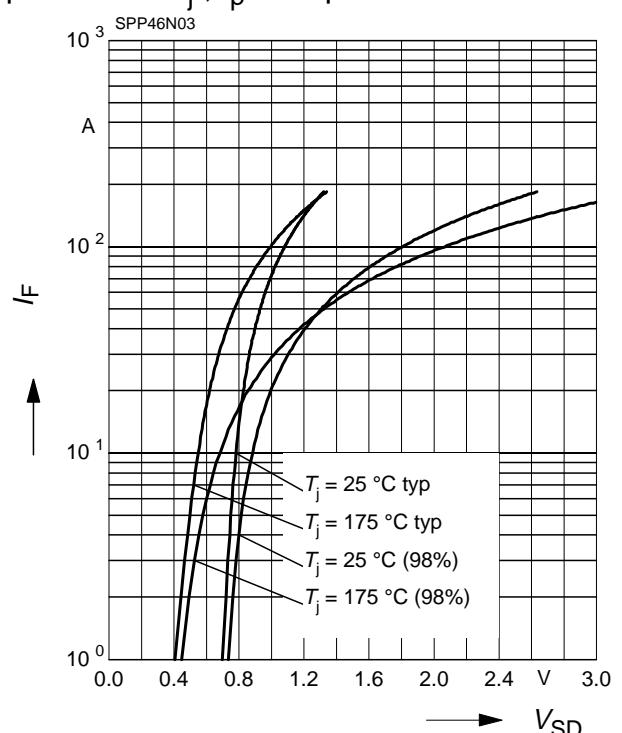
parameter: $V_{GS} = 0 \text{ V}$, $f = 1 \text{ MHz}$



Forward characteristics of reverse diode

$$I_F = f(V_{SD})$$

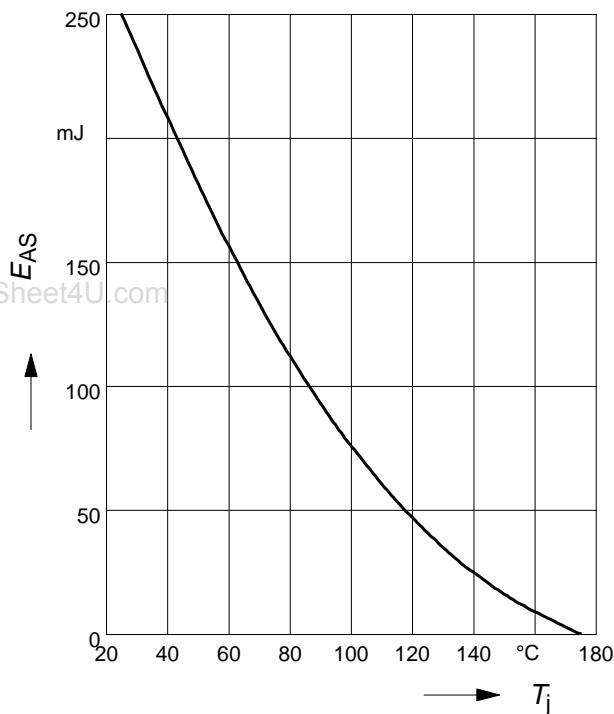
parameter: T_j , $t_p = 80 \mu\text{s}$



Avalanche Energy $E_{AS} = f(T_j)$

parameter: $I_D = 46 \text{ A}$, $V_{DD} = 25 \text{ V}$

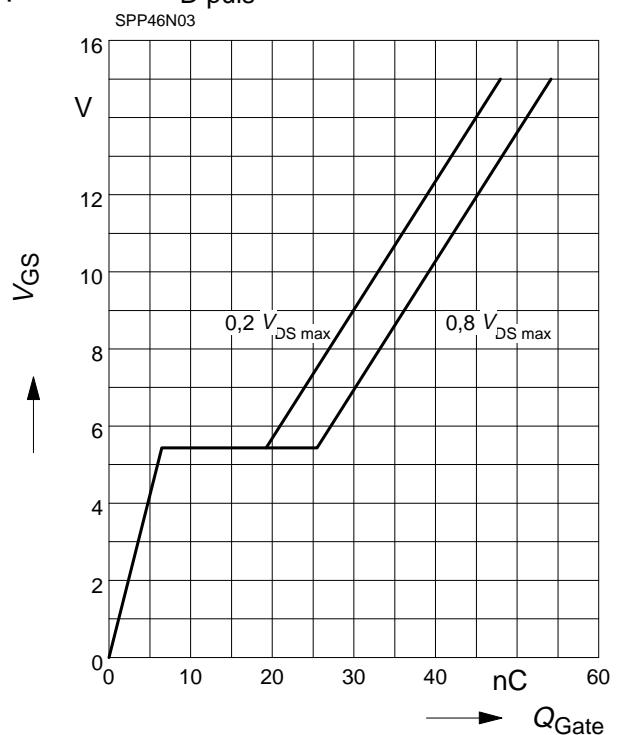
$R_{GS} = 25 \Omega$



Typ. gate charge

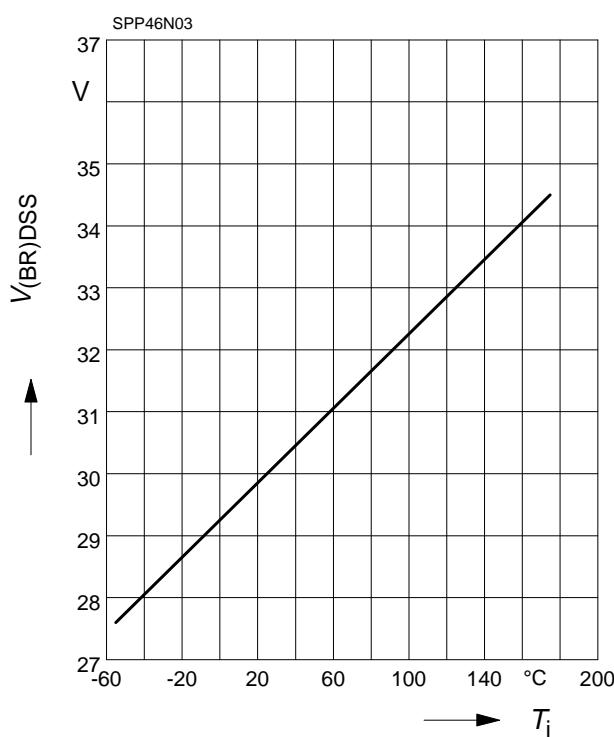
$V_{GS} = f(Q_{Gate})$

parameter: $I_D \text{ puls} = 46 \text{ A}$



Drain-source breakdown voltage

$V_{(BR)DSS} = f(T_j)$



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